- All Outputs Are High for Invalid Input Conditions
- Also for Application as
   4-Line-to-16-Line Decoders
   3-Line-to-8-Line Decoders
- Diode-Clamped Inputs

	TYPICAL	TYPICAL
TYPES	POWER	PROPAGATION
	DISSIPATION	DELAYS
'42A	140 mW	17 ns
'LS42	35 mW	17 ns

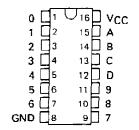
### description

These monolithic BCD-to-decimal decoders consist of eight inverters and ten four-input NAND gates. The inverters are connected in pairs to make BCD input data available for decoding by the NAND gates. Full decoding of valid input logic ensures that all outputs remain off for all invalid input conditions.

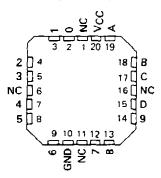
The '42A and 'LS42 feature inputs and outputs that are compatible for use with most TTL and other saturated low-level logic circuits. DC noise margins are typically one volt.

The SN5442A and SN54LS42 are characterized for operation over the full military temperature range of  $-55\,^{\circ}\text{C}$  to  $125\,^{\circ}\text{C}$ . The SN7442A and SN74LS42 are characterized for operation from  $0\,^{\circ}\text{C}$  to  $70\,^{\circ}\text{C}$ .

SN5442A, SN54LS42...J OR W PACKAGE SN7442A...N PACKAGE SN74LS42...D OR N PACKAGE (TOP VIEW)



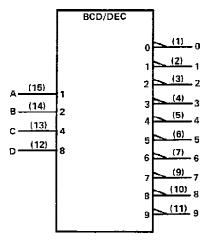
SN54LS42 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

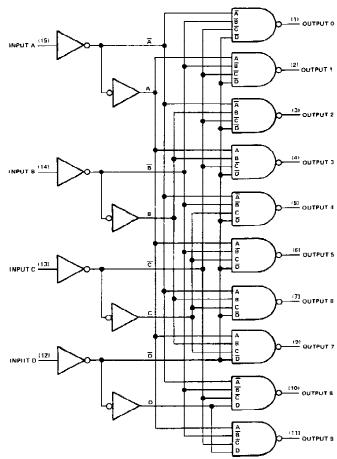
# SN5442A, SN54LS42, SN7442A, SN74LS42 4-LINE BCD TO 10-LINE DECIMAL DECODERS

logic symbol†



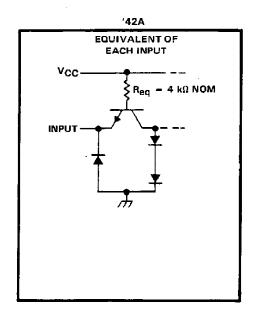
<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

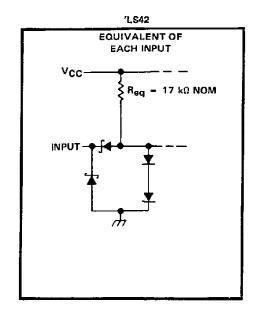
## logic diagram (positive logic)

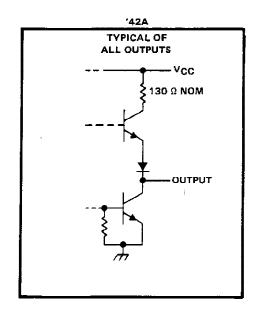


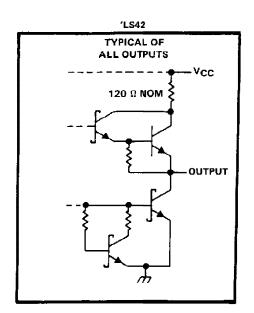
Pin numbers shown are for D. J. N. and W packages.

## schematics of inputs and outputs









### **FUNCTION TABLE**

NO	BCD INPUT							DEC	MAL (	OUTPL	JT			
NO.	D	C	8	A	0	7	2	3	4	5	6	7	8	9
0	L	L	L	Ļ	L	Н	Н	Н	Н	Н	H	Н	Н	H
1	L	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н	Н	Н
2	L	L	Н	L	Н	H	L	Н	Н	н	Н	H	Н	Η.
3	L	L	Н	Н	н	н	Н	L	Н	Н	Н	Н	Н	Н
4	L	Н	L	L	н	Н	H	H	L	Н	Н	Н	Н	Н
5	L	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н	Н	H
6	L	Н	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н	н
7	L	Н	Н	Н	н	H	Н	Н	Н	Н	Н	L	Н	н
8	Н	L	L	L	н	Н	Н	Н	н	н	н	Н	L	н
9	H	L	L	Н	Н	Н	Н	Н	Н	H	Н	H	Н	L
	Н	L	Н	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н
	н	L	н	Н	H	Н	Н	Н	Н	н	н	н	Н	н
	Н	H	L	L	н	Н	Н	Н	Н	H	Н	Н	н	н
NVALID	Н	Н	L	Н	н	Н	Н	Н	Н	Н	H	Н	Н	н
=	Н	Н	Н	L	н	Н	Н	Н	Н	Н	Н	H	Н	Н
	н	Н	H	Н	τ	н	Н	Н	н	H_	н	н	Н	н

H = high level, L = low level

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)
Input voltage: '42A
'LS42 7 V
Operating free-air temperature range: SN5442A, SN54LS42
SN7442A, SN74LS42 0 °C to 70 °C
Storage temperature range65 °C to 150 °C

NOTE 1: Voltage values are with respect to network ground terminal.

### recommended operating conditions

	s	SN5442A			SN7442A			
	MIN	NOM	MAX	MIN	NOM	MAX		
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	٧	
High-level output current, IOH			-800			-800	μА	
Low-level output current, IOL			16			16	mΑ	
Operating free-air temperature, TA	-55		125	0		70	ĴÇ	

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS†	s	N5442	A	!	UNIT		
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	İ
ViH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.8			0.8	٧
VΙΚ	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -12 mA			-1.5			-1.5	٧
νон	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> =800 μA	2.4	3.4		2.4	3.4		٧
VOL	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 16 mA		0.2	0.4		0.2	0.4	٧
Ц	Input current at maximum input voltage	VCC = MAX, V1 = 5.5 V			1			1	mΑ
119	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4 V			40			40	μА
I <sub>I</sub> L	Low level input current	V <sub>CC</sub> = MAX, V <sub>1</sub> = 0.4 V			<b>-1.6</b>	}		-1.6	mA
los	Short-circuit output current 8	V <sub>CC</sub> = MAX	-20		-55	-18		-55	mА
Icc	Supply current	VCC = MAX, See Note 2		28	41		28	56	mA

TFor conditions shown as MIN or MAX, use the appropriate values specified under recommended operating conditions.

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{ C}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPHL	Propagation delay time, high-to-low-level output from A, B, C, or D through 2 levels of logic			14	25	ns
tPHL.	Propagation delay time, high-to-low-level output from A, B, C, or D through 3 levels of logic	C <sub>L</sub> = 15 pF,		17	30	пѕ
† <b>PL</b> H	Propagation delay time, low-to-high-level output from A, B, C, and D through 2 levels of logic	R <sub>L</sub> = 400 Ω, See Note 3		10	25	ns
<sup>t</sup> PLH	Propagation delay time, low-to-high-level output from A, B, C, and D through 3 levels of logic			17	30	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



<sup>‡</sup>All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C. § Not more than one output should be shorted at a time.

NOTE 2:  $I_{\mbox{CC}}$  is measured with all outputs open and all inputs grounded.

# SN54LS42, SN74LS42 4-LINE BCD TO 10-LINE DECIMAL DECODERS

## recommended operating conditions

	s	SN54LS42					1
	MIN	NOM	MAX	MIN	MOM	MAX	UNIT
Supply voltage, VCC	4.5	5	5.5	4.75	5	5.25	٧
High-level output current, IOH			-400			-400	μА
Low-level output current, IOL			4			8	mΑ
Operating free-air temperature, TA	-55		125	0		70	°С

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†			S	N54LS4	12	S	I			
	PARAMETER	TEST CONDITIONS			MIN TYP‡		MAX	MIN TYP!		MAX	UNIT	
Vін	High-level input voltage				2			2			٧	
VIL	Low-level input voltage						0.7			8.0	٧	
Vικ	Input clamp voltage	VCC = MIN.	l <sub>1</sub> = -18 m/	4			-1.5			-1.5	٧	
Vон	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = V <sub>IL</sub> max,	V <sub>IH</sub> = 2 V, I <sub>OH</sub> = -400	ΙμΑ	2.5	3.5		2.7	3.5		٧	
1/2.	I am land an anticolare	V <sub>CC</sub> = MIN,	V <sub>IH</sub> = 2 V,	I <sub>OL</sub> = 4 mA		0.25	0.4		0.25	0.4	V	
VOL	Low-level output voltage	VIL = VIL max		I <sub>OL</sub> = 8 mA					0.35	0.5	ľ	
ΙĮ	Input current at maximum input voltage	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 7 V				0.1		•	0.1	mA	
Чн	High-level input current	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 2.7 V				20			20	μΑ	
li L	Low-level input current	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 0.4 V				-0.4			-0.4	mΑ	
los	Short-circuit output current §	V <sub>CC</sub> = MAX			-20		-100	-20		-100	mA	
lcc	Supply current	VCC = MAX,	See Note 2			7	13		7	13	mA	

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
†PHL	Propagation delay time, high-to-low-level			15	25	ns
	output from A, B, C, or D through 2 levels of logic  Propagation delay time, high-to-low-level		-			
<b>t</b> PH ∟	output from A, B, C, or D through 3 levels of logic	C <sub>L</sub> = 15 pF.	- 1	20	30	ns
†PLH	Propagation delay time, low-to-high-level	$R_L = 2 kΩ$ , See Note 3		15	25	ns
1F E F	output from A, B, C, and D through 2 levels of logic		<u> </u>			L
tPLH	Propagation delay time, low-to-high-level output from A, B, C, and D through 3 levels of logic			20	30	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value spacified under recommended operating conditions. ‡All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C. § Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second,

NOTE 2.  $I_{CC}$  is measured with all outputs open and inputs grounded.

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